


<b>Search Notes</b>  	<b>Application/Control No.</b>  10781041	<b>Applicant(s)/Patent Under Reexamination</b>  WANG ET AL.
	<b>Examiner</b>  Betsy L. Deppe	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	260	7/3/08	B. Deppe
370	208, 210, 343, 344, 480	7/3/08	B. Deppe

SEARCH NOTES		
Search Notes	Date	Examiner
Text search (USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM-TDB)	7/3/08	B. Deppe
Updated inventors name search	3/30/09	B. Deppe
Updated class/subclass search	3/30/09	B. Deppe
Text search (USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM-TDB)	3/30/09	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	Text search (USPAT; US-PGPUB)	3/30/09	B. Deppe

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